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	Complete if Known	
Application Number	10/817,089	
Filing Date	April 2, 2004	
First Named Inventor	Getty et al.	
Group Art Unit	Unknown	
Examiner Name	Unknown	
Attorney Docket Number	CL2127 US NA	

	_			U.S. PATENT DOCUM	MENTS	
		U.S. Pa	itent Document	Name of Patentee or Applicant	Date of Publication of	Pages Columns Lines Where Releases
Examiner tnitlats *	Cite No.	Number	Kind Code <sup>2</sup> (if known)	of Cited Document	Cited Document  NM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
HARN		5,945,8	332	Motorola, Inc.	08/31/1999	
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				FOREIG	N PATENT DOCU	MENTS		
Examiner Initiats*	Cite No.1	Foreign Patent Document		Name of Patentee	Date of Publication of	Pages, Columns, Lines,		
		Office <sup>3</sup>	Number <sup>4</sup>	Kind Code <sup>5</sup> (if known)	or Applicant of Cited Document	Cited Document MM-DD-YYYY	Where Relevant Passages or Relevant Figures Appear	T <sub>6</sub>
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Examiner Signature	Hoar-An D. Nguyen	Date Considered	4126105

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Substitut	e for form 1448A/PT(	)			Complete if Known	•
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INFO	PRMATION	DIS	CLOSURE	Filing Date	April 2, 2004	
STA	TEMENT B	Y A	PPLICANT	First Named Inventor	Getty et al.	
			•	Group Art Unit	Unknown	
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Sheet	2	of	3	Attorney Docket Number	CL2127 US NA	

		OTHER PRIOR ART NON PATENT LITERATURE DOCUMENTS	
Examiner Initials *	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T²
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Examiner Signature	Hour-An D. Nguyen	Date Considered	4/26/05
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Group Art Unit

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